

FCC SDoC Test Report

For

Applicant Name: SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO., LTD

A2 2F BUILDING ENET NEW INDUSTRIAL PARK, DAFU

Address: INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX

China

EUT Name: Smart Phone Brand Name: OUKITEL WP32

Series Model Number: Refer to section 2

Issued By

Company Name: BTF Testing Lab (Shenzhen) Co., Ltd.

F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen,

China

Report Number: BTF230913E00601

Test Standards: 47 CFR Part 15, Subpart B

Test Conclusion: Pass

FCC ID: 2ANMU-WP32SPUT

Test Date: 2023-09-15 to 2023-10-09

Date of Issue: 2023-10-10

Prepared By:

Address:

Chris Liu / Project Engineer

hyiS

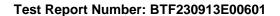
Date: 2023-10-10

Approved By:

Ryan.CJ / EMC Manager

Date: 2023-10-10

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Revision History			
Version	Issue Date	Revisions Content	
R_V0	2023-10-10	Original	
Note: Once the	revision has been made, then pre	vious versions reports are invalid.	

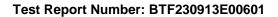




Table of Contents

1	INTR	RODUCTION	4
	1.1	Identification of Testing Laboratory	4
	1.2	Identification of the Responsible Testing Location	4
	1.3	Announcement	
2	PRO	DDUCT INFORMATION	
	2.1	Application Information	
	2.2 2.3	Manufacturer InformationFactory Information	
	2.3 2.4	General Description of Equipment under Test (EUT)	5
	2.5	Technical Information	5
3	SUM	MMARY OF TEST RESULTS	6
	3.1	Test Standards	
	3.2	Uncertainty of Test	
	3.3	Summary of Test Result	6
4	TES	T CONFIGURATION	7
	4.1	Test Equipment List	
	4.2	Test Auxiliary Equipment	
	4.3	Test Modes	
5		SSION TEST RESULTS (EMI)	
	5.1	Conducted emissions on AC mains	
		5.1.1 E.U.T. Operation:	
		5.1.2 Test Setup Diagram: 5.1.3 Test Data:	
	5.2	Radiated emissions (Below 1GHz)	
	0.2	5.2.1 E.U.T. Operation:	
		5.2.2 Test Setup Diagram:	
		5.2.3 Test Data:	
	5.3	Radiated emissions (Above 1GHz)	
		5.3.1 E.U.T. Operation:	
		5.3.2 Test Setup Diagram:	
		5.3.3 Test Data:	
6	TES	T SETUP PHOTOSCONSTRUCTIONAL DETAILS (EUT PHOTOS)	18 20
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Test Report Number: BTF230913E00601

1 Introduction

1.1 Identification of Testing Laboratory

Company Name: BTF Testing Lab (Shenzhen) Co., Ltd.			
Address: F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tanto Community, Songgang Street, Bao'an District, Shenzhen, China			
Phone Number: +86-0755-23146130			
Fax Number: +86-0755-23146130			

1.2 Identification of the Responsible Testing Location

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Phone Number:	+86-0755-23146130
Fax Number:	+86-0755-23146130
FCC Registration Number:	518915
Designation Number:	CN1330

1.3 Announcement

- (1) The test report reference to the report template version v0.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing, reviewing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) This document may not be altered or revised in any way unless done so by BTF and all revisions are duly noted in the revisions section.
- (5) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.
- (6) The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.



Test Report Number: BTF230913E00601

2 Product Information

2.1 Application Information

Company Name:	SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO., LTD
Address:	A2 2F BUILDING ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China

2.2 Manufacturer Information

Company Name: SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO., LTD	
Address:	A2 2F BUILDING ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China

2.3 Factory Information

Company Name: SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO., LTD				
I Address.	A2 2F BUILDING ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China			

2.4 General Description of Equipment under Test (EUT)

EUT Name:	Smart Phone
Test Model Number:	WP32
Series Model Number:	WP32 S, WP32 Pro, WP32 TITAN
Description of Model name differentiation:	Only the model name is different, the others are the same.
Hardware Version:	SC6012_MB_V1.1.0
Software Version:	OUKITEL_WP32_EEA_V04

2.5 Technical Information

Power Supply:	AC 120V 60Hz
Power Adaptor:	Input: 100-240V~50/60Hz 0.3A Output: 5.0V=2.0A



Test Report Number: BTF230913E00601

3 Summary of Test Results

3.1 Test Standards

The tests were performed according to following standards: **47 CFR Part 15, Subpart B:** Unintentional Radiators

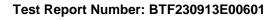
3.2 Uncertainty of Test

Item	Measurement Uncertainty	
Conducted Emission (150 kHz-30 MHz)	±2.64dB	
Radiated Emissions (30M - 1GHz)	±4.12dB	
Radiated Emissions (above 1GHz)	1-6GHz: ±3.94dB 6-18GHz: ±4.16dB	

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

3.3 Summary of Test Result

Item	Standard	Requirement	Result
Conducted emissions on AC mains	47 CFR Part 15, Subpart B	15.107, Class B	Pass
Radiated emissions (Below 1GHz)	47 CFR Part 15, Subpart B	15.109, Class B	Pass
Radiated emissions (Above 1GHz)	47 CFR Part 15, Subpart B	15.109, Class B	Pass



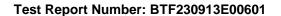


Test Configuration

Test Equipment List

Conducted emissions on AC mains					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Pulse Limiter	SCHWARZBECK	VTSD 9561-F	00953	2022-11-24	2023-11-23
Coaxial Switcher	SCHWARZBECK	CX210	CX210	2022-11-24	2023-11-23
V-LISN	SCHWARZBECK	NSLK 8127	01073	2022-11-24	2023-11-23
LISN	AFJ	LS16/110VAC	16010020076	2023-02-23	2024-02-22
EMI Receiver	ROHDE&SCHWA RZ	ESCI3	101422	2022-11-24	2023-11-23

Radiated emissions (I					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Coaxial cable Multiflex 141	Schwarzbeck	N/SMA 0.5m	517386	2023-03-24	2024-03-23
Preamplifier	SCHWARZBECK	BBV9744	00246	2022-11-24	2023-11-23
RE Cable	REBES Talent	UF1-SMASMAM-1 0m	21101566	2022-11-24	2023-11-23
RE Cable	REBES Talent	UF2-NMNM-10m	21101570	2022-11-24	2023-11-23
RE Cable	REBES Talent	UF1-SMASMAM-1 m	21101568	2022-11-24	2023-11-23
RE Cable	REBES Talent	UF2-NMNM-1m	21101576	2022-11-24	2023-11-23
RE Cable	REBES Talent	UF2-NMNM-2.5m	21101573	2022-11-24	2023-11-23
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	/	/
Horn Antenna	SCHWARZBECK	BBHA9170	01157	2021-11-28	2023-11-27
EMI TEST RECEIVER	ROHDE&SCHWA RZ	ESCI7	101032	2022-11-24	2023-11-23
SIGNAL ANALYZER	ROHDE&SCHWA RZ	FSQ40	100010	2022-11-24	2023-11-23
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	/	1
Broadband Preamplilifier	SCHWARZBECK	BBV9718D	00008	2023-03-24	2024-03-23
Horn Antenna	SCHWARZBECK	BBHA9120D	2597	2022-05-22	2024-05-21
EZ_EMC	Frad	FA-03A2 RE+	/	/	/
POSITIONAL CONTROLLER	SKET	PCI-GPIB	1	/	/
Log periodic antenna	SCHWARZBECK	VULB 9168	01328	2021-11-28	2023-11-27



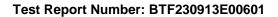


4.2 Test Auxiliary Equipment

Title	Manufacturer	Model No.	Serial No.
/	/	/	/

Test Modes

No.	Test Modes	Description
TM1	Charging + Video recording	
TM2	Charging + Video play	
TM3	Date transmission	





5 Emission Test Results (EMI)

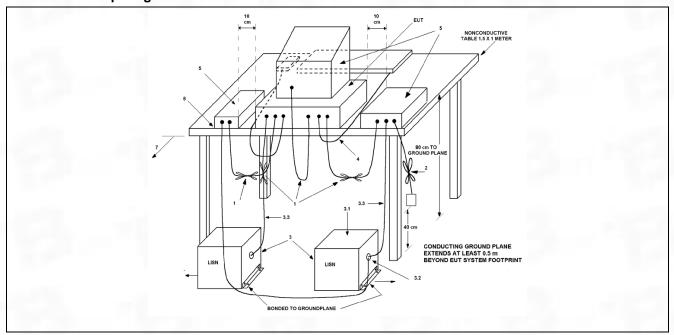
5.1 Conducted emissions on AC mains

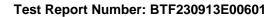
Test Requirement:	15.107, Class B								
Test Method:	ANSI C63.4-2014	ANSI C63.4-2014							
	Frequency of emission (MHz)	Conducted limit (d	dBμV)						
		Quasi-peak	Average						
Toot Limits	0.15-0.5	66 to 56*	56 to 46*						
Test Limit:	0.5-5	56	46						
	5-30	60	50						
	*Decreases with the logarithm of	*Decreases with the logarithm of the frequency.							
Procedure:		An initial pre-scan was performed with peak detector.Quasi-Peak or Average measurement were performed at the frequencies with maximized peak emission were detected.							
	Remark: Level= Read Level+ Cable	e Loss+ LISN Factor							

5.1.1 E.U.T. Operation:

Operating Environment:	
Temperature:	24 °C
Humidity:	48.6 %
Atmospheric Pressure:	1010 mbar

5.1.2 Test Setup Diagram:

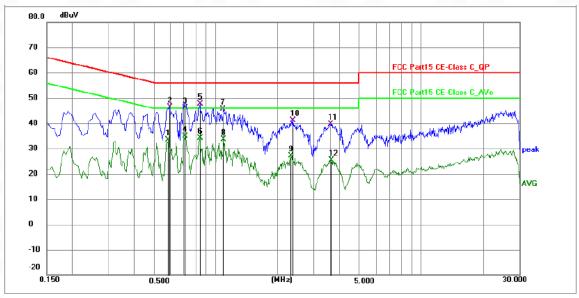




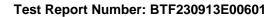


5.1.3 Test Data:

TM1 / Line: Line

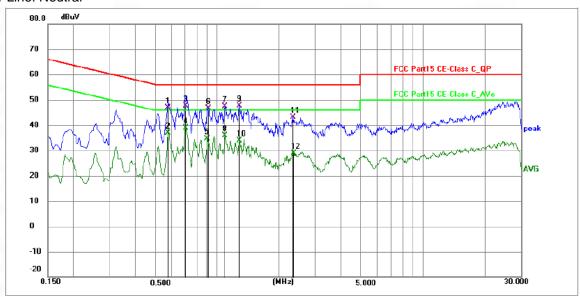


No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1	0.5865	22.74	10.66	33.40	46.00	-12.60	AVG	Р	
2	0.5955	35.67	10.67	46.34	56.00	-9.66	QP	Р	
3	0.7080	35.47	10.73	46.20	56.00	-9.80	QP	Р	
4	0.7080	24.18	10.73	34.91	46.00	-11.09	AVG	Р	
5	* 0.8385	36.81	10.75	47.56	56.00	-8.44	QP	Р	
6	0.8385	23.34	10.75	34.09	46.00	-11.91	AVG	Р	
7	1.0859	34.77	10.77	45.54	56.00	-10.46	QP	Р	
8	1.0905	22.96	10.77	33.73	46.00	-12.27	AVG	Р	
9	2.3325	16.35	10.70	27.05	46.00	-18.95	AVG	Р	
10	2.3640	30.39	10.70	41.09	56.00	-14.91	QP	Р	
11	3.6105	29.00	10.72	39.72	56.00	-16.28	QP	Р	
12	3.6420	14.68	10.72	25.40	46.00	-20.60	AVG	Р	

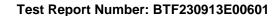




TM1 / Line: Neutral



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1	0.5775	36.24	10.66	46.90	56.00	-9.10	QP	Р	
2	0.5775	26.30	10.66	36.96	46.00	-9.04	AVG	Р	
3	0.7035	36.97	10.73	47.70	56.00	-8.30	QP	Р	
4 *	0.7035	28.13	10.73	38.86	46.00	-7.14	AVG	Р	
5	0.8970	23.97	10.76	34.73	46.00	-11.27	AVG	Р	
6	0.9060	35.76	10.76	46.52	56.00	-9.48	QP	Р	
7	1.0905	36.68	10.77	47.45	56.00	-8.55	QP	Р	
8	1.0905	25.08	10.77	35.85	46.00	-10.15	AVG	Р	
9	1.2795	37.00	10.75	47.75	56.00	-8.25	QP	Р	
10	1.2885	23.25	10.75	34.00	46.00	-12.00	AVG	Р	
11	2.3415	32.43	10.70	43.13	56.00	-12.87	QP	Р	
12	2.3550	18.19	10.70	28.89	46.00	-17.11	AVG	Р	





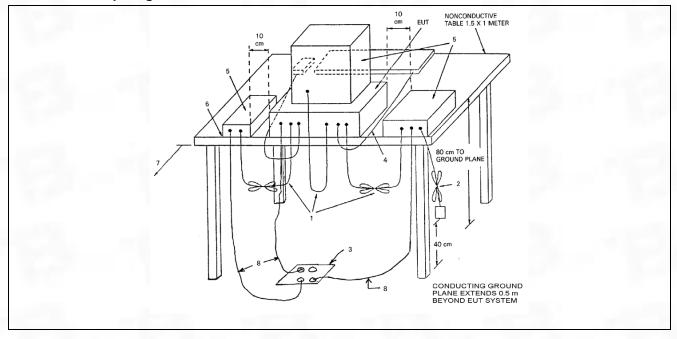
5.2 Radiated emissions (Below 1GHz)

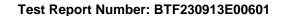
Test Requirement:	15.109, Class B								
Test Method:	ANSI C63.4-2014								
	Except for Class A digital devices, the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:								
	Frequency of emission	Field stre	ngth	Field str	ength @10m				
T. (11)	(MHz)	@3m	(dD)//	(AMA) (IDAMA)					
Test Limit:		(uV/m)	(dBuV/ m)	(uV/m)	(dBuV/m)				
	30 – 88	100	40	30	29.5				
	88 – 216	150	43.5	45	33.1				
	216 – 960	200	46	60	35.6				
	Above 960	500	54	150	43.5				
Procedure:	An initial pre-scan was performed in the chamber using the spectrum analyser in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by BiConiLog antenna with 2 orthogonal polarities. Remark: Level= Read Level+ Cable Loss+ Antenna Factor- Preamp Factor								

5.2.1 E.U.T. Operation:

Operating Environment:	
Temperature:	24 °C
Humidity:	48.6 %
Atmospheric Pressure:	1010 mbar

5.2.2 Test Setup Diagram:

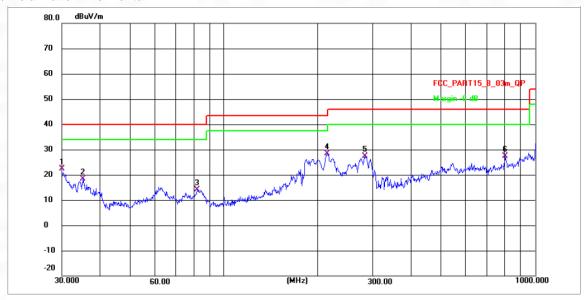




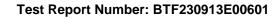


5.2.3 Test Data:

TM1 / Polarization: Horizontal

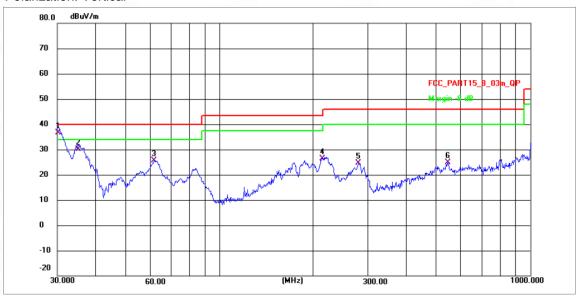


No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	30.0526	41.08	-18.81	22.27	40.00	-17.73	QP	Р
2	35.1894	36.75	-18.47	18.28	40.00	-21.72	QP	Р
3	81.9268	31.89	-17.79	14.10	40.00	-25.90	QP	Р
4 *	214.1385	55.02	-26.71	28.31	43.50	-15.19	QP	Р
5	282.9852	52.84	-25.57	27.27	46.00	-18.73	QP	Р
6	801.7863	51.08	-23.69	27.39	46.00	-18.61	QP	Р

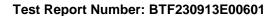




TM1 / Polarization: Vertical



N	No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
	1 *	30.2111	54.96	-18.36	36.60	40.00	-3.40	QP	Р
	2	35.0663	50.73	-20.63	30.10	40.00	-9.90	QP	Р
	3	61.5618	45.77	-20.13	25.64	40.00	-14.36	QP	Р
	4	214.8907	53.09	-26.68	26.41	43.50	-17.09	QP	Р
	5	280.5152	50.11	-25.60	24.51	46.00	-21.49	QP	Р
	6	543.2742	46.53	-21.59	24.94	46.00	-21.06	QP	Р





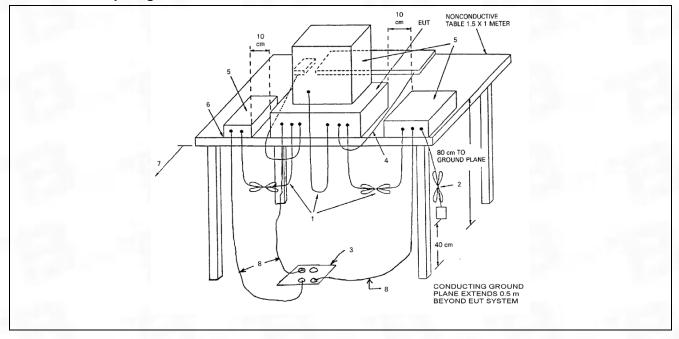
5.3 Radiated emissions (Above 1GHz)

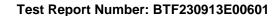
Test Requirement:	15.109, Class B								
Test Method:	ANSI C63.4-2014								
	Frequency of emission (MHz)	Field streng	ıth @3m						
Test Limit:	Section 1	Average (uV/m)	Average(d BuV/m)	Peak (dBuV/m)					
	Above 1GHz	500	54	74					
Procedure:	An initial pre-scan was performed in peak detection mode. For below 1G conducted based on the peak sweet antenna with 2 orthogonal polarities were conducted based on the peak antenna with 2 orthogonal polarities Remark: Level= Read Level+ Cable	Hz test, Quasi p graph. The E . For above 10 sweep graph.	i-peak measure EUT was measu BHz test, Averao The EUT was n	ments were ired by BiConiLog ge measurements neasured by Horn					

5.3.1 E.U.T. Operation:

Operating Environment:					
Temperature:	24 °C				
Humidity:	48.6 %				
Atmospheric Pressure:	1010 mbar				

5.3.2 Test Setup Diagram:

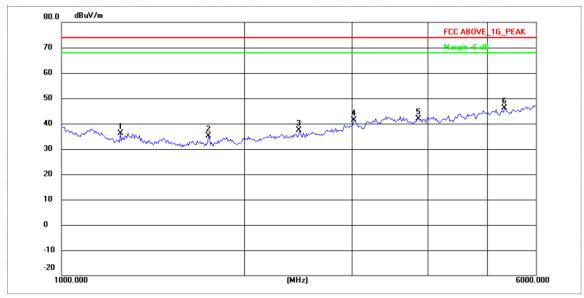




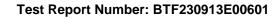


5.3.3 Test Data:

TM1 / Polarization: Horizontal

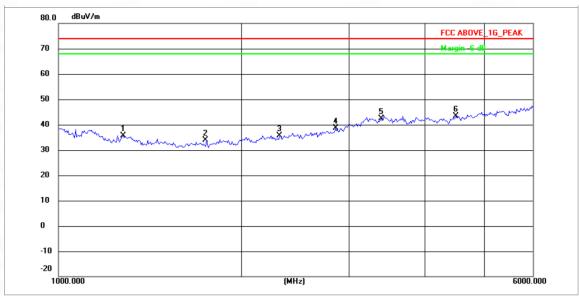


No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	1248.794	66.36	-30.33	36.03	74.00	-37.97	peak	Р
2	1742.717	66.49	-31.32	35.17	74.00	-38.83	peak	Р
3	2458.283	67.80	-30.42	37.38	74.00	-36.62	peak	Р
4	3015.374	70.94	-29.50	41.44	74.00	-32.56	peak	Р
5	3861.233	71.00	-29.02	41.98	74.00	-32.02	peak	Р
6 *	5330.811	73.21	-27.09	46.12	74.00	-27.88	peak	Р

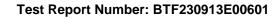




TM1 / Polarization: Vertical

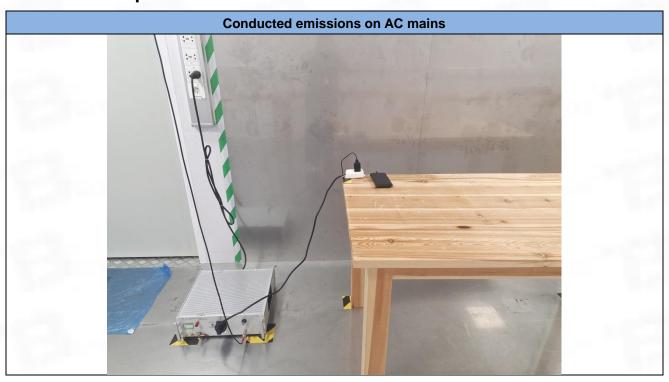


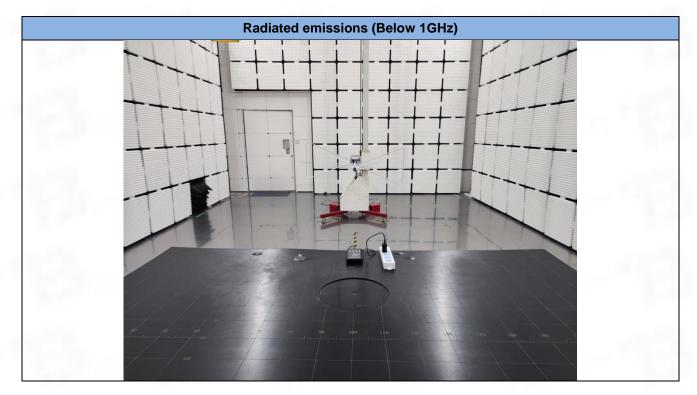
No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	1275.935	66.07	-30.49	35.58	74.00	-38.42	peak	Р
2	1748.973	65.28	-31.32	33.96	74.00	-40.04	peak	Р
3	2312.995	66.09	-30.57	35.52	74.00	-38.48	peak	Р
4	2847.347	68.52	-29.77	38.75	74.00	-35.25	peak	Р
5	3381.761	71.63	-29.16	42.47	74.00	-31.53	peak	Р
6 *	4488.392	72.26	-28.79	43.47	74.00	-30.53	peak	Р

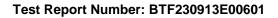




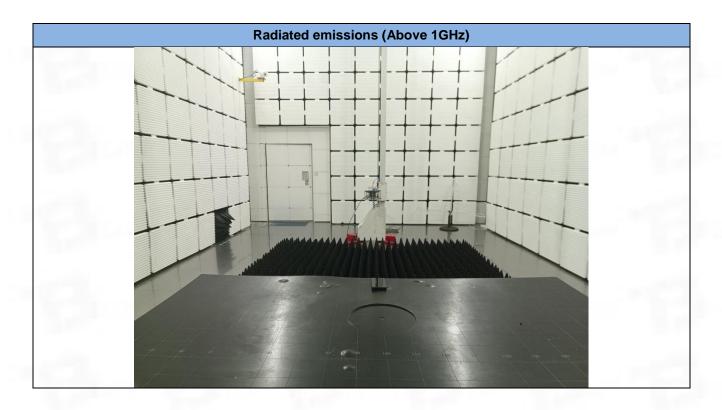
Test Setup Photos 6

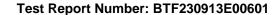










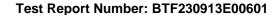




7 EUT Constructional Details (EUT Photos)



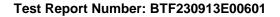






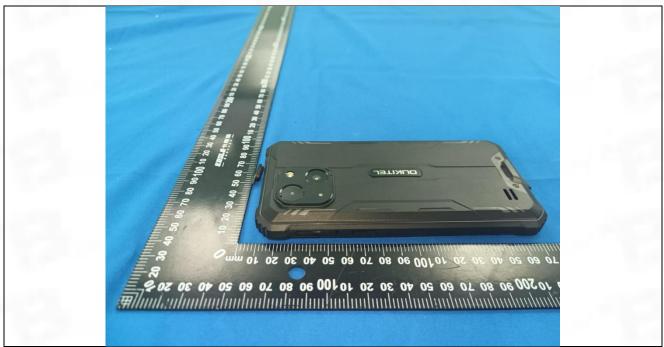


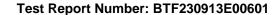








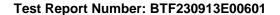




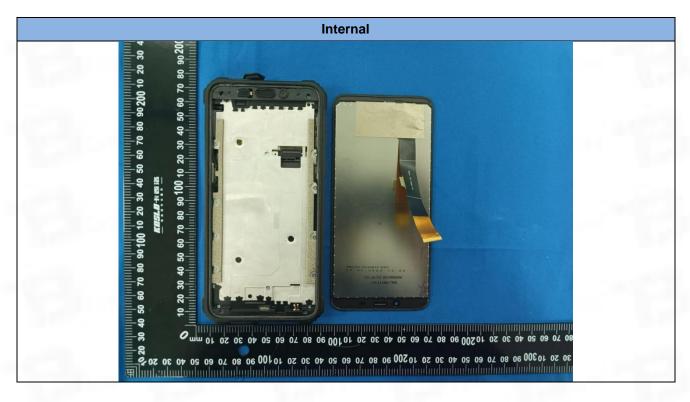




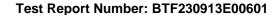




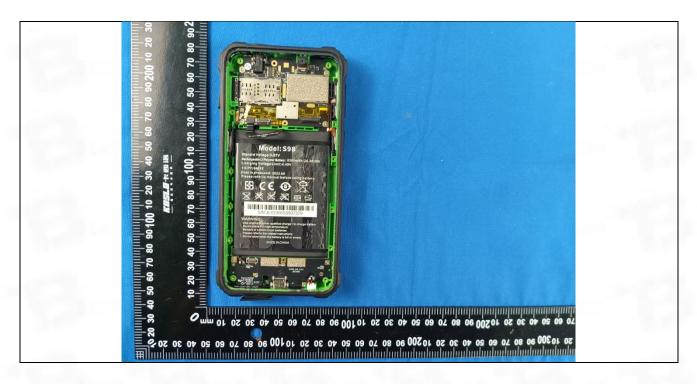




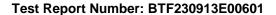




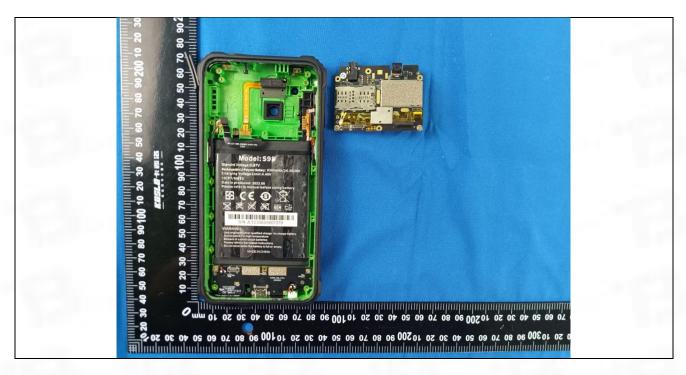


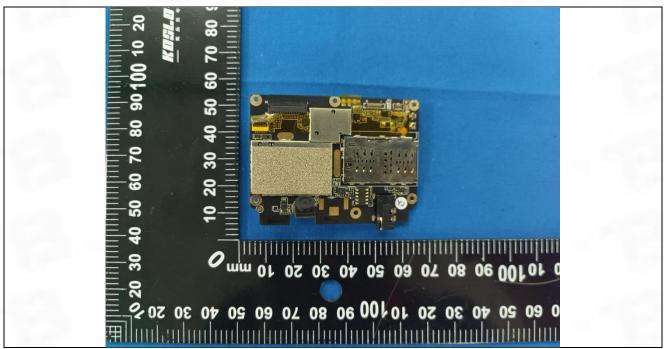


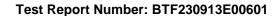




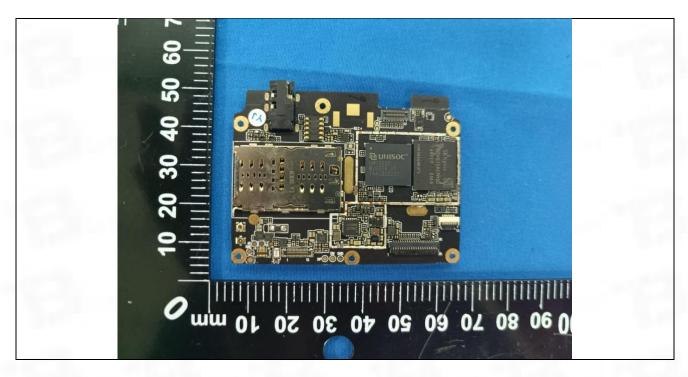


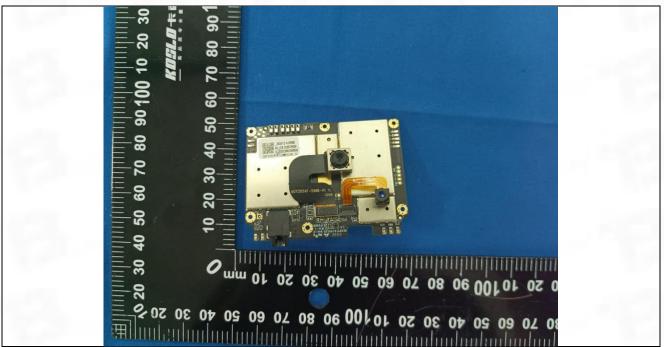


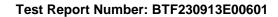




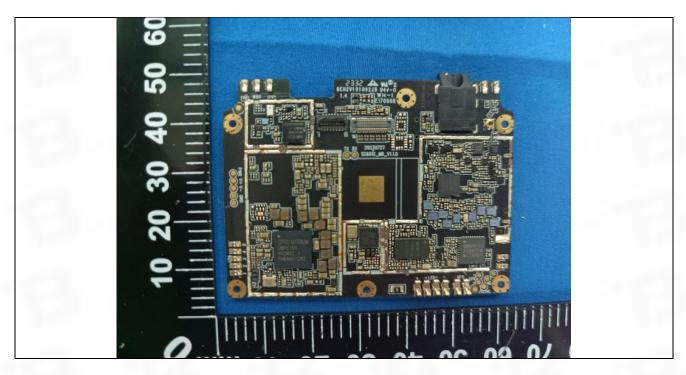


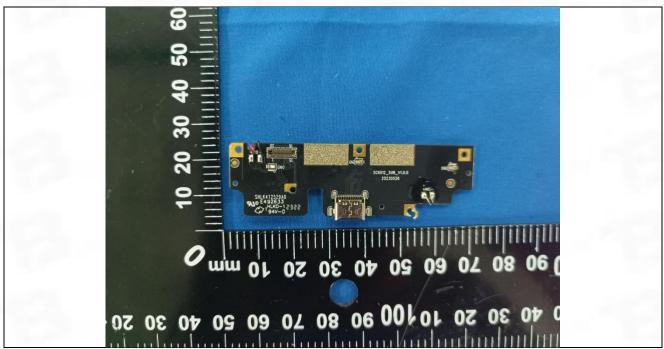


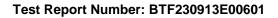




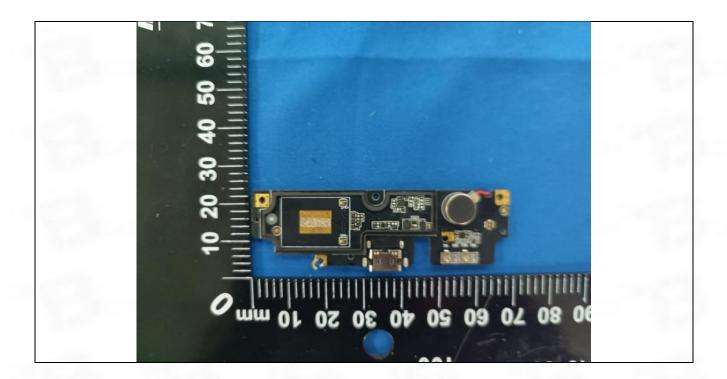


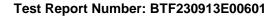
















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